Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/672,357	FU ET AL.	
Examiner	Art Unit	
Binh X. Tran	1765	

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Updated search	3/15/2006	ВТ	